

N-Channel Enhancement-Mode MOSFET

Designed for handheld two-way radio applications with frequencies from 136 to 941 MHz. The high gain, ruggedness and Broadband performance of this device make it ideal for large-signal, common-source amplifier applications in handheld radio equipment.

**136–941 MHz, 0.15W, 3.7 V
BROADBAND RF POWER
TRANSISTOR**

Typical Broadband EVB Performance ($I_{DQ}=90\text{mA}$, $T_A = 25^\circ\text{C}$, CW)

V_{DS}	Freq.	G_{max}	P_{out}		PAE
[V]	[MHz]	[dB]	[dBm]	[mW]	[%]
3.7	400	17.5	22.0	160	53.4
	440	16.0	23.2	210	67.4
	480	15.4	23.2	210	64.4
	520	13.8	23.0	200	61.3

- Capable of Handling 20:1 VSWR @ 6.0 Vdc, 0.2 Watts, CW

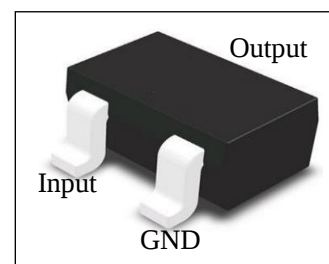


Figure 1. Pin Connections

Features

- Characterized for Operation from 136 to 941 MHz
- Unmatched Input and Output Allowing Broad Frequency Range Utilization
- Integrated ESD Protection
- Broadband – Full Power Across the Band
- Exceptional Thermal Performance
- Extreme Ruggedness

Typical Applications

- Output Stage VHF Band Handheld Radio
- Output Stage UHF Band Handheld Radio
- Output Stage for 700–800 MHz Handheld Radio
- Driver for 10–1000 MHz Applications

Table1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	-0.5, +20	Vdc
Gate-Source Voltage	V_{GS}	-0.5, +8	Vdc
Operating Voltage	V_{DD}	0, +6	Vdc
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_C	-40 to +150	°C
Operating Junction Temperature	T_J	-40 to +150	°C
Power Dissipation @TC=25°C	PD	0.25	Watts

Table 2. ESD Protection Characteristic

Test Methodology	Class
Human Body Model (per JESD22--A114)	2, passes 2500 V
Machine Model (per EIA/JESD22--A115)	A, passes 100 V
Charge Device Model (per JESD22--C101)	IV, passes 2000 V

Table 3. Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ.	Max	Unit
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Off Characteristics

Gate-Source Leakage Current ($V_{GS}=5\text{Vdc}$, $V_{DS}=0\text{Vdc}$)	I_{GSS}	-	-	500	nAdc
Zero Gate Voltage Drain Leakage Current ($V_{DS}=16\text{Vdc}$, $V_{GS}=0\text{Vdc}$)	I_{DSS}	-	-	100	nAdc
Zero Gate Voltage Drain Leakage Current ($V_{DS}=3.7\text{Vdc}$, $V_{GS}=0\text{Vdc}$)	I_{DSS}	-	-	100	nAdc

On Characteristics

Gate Threshold Voltage ($V_{DS}=3.7\text{Vdc}$, $I_D=1\text{mA}$)	$V_{GS(th)}$	1.6	1.8	2.0	Vdc
Gate Quiescent Voltage ($V_{DD}=3.7\text{Vdc}$, $I_D=90\text{mA}$ Measured in Functional Test)	$V_{GS(Q)}$	2.2	2.6	2.8	Vdc
Drain-Source On-Voltage ($V_{GS}=5\text{Vdc}$, $I_D=100\text{mA}$)	$V_{DS(ON)}$	-	0.28	-	Vdc

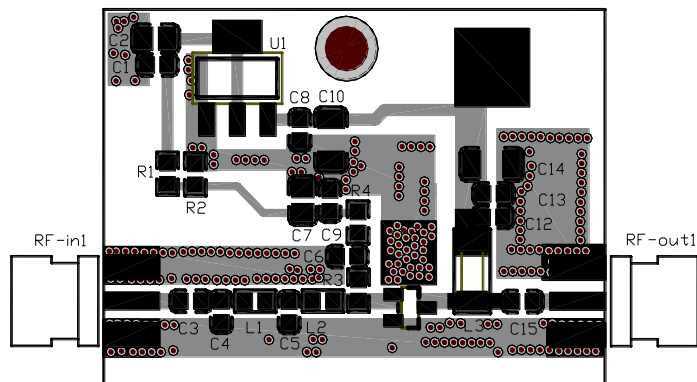
Dynamic Characteristics

Reverse Transfer Capacitance ($V_{DG}=3.7\text{V}$, Level=30mVac@1MHz)	C_{rss}	-	0.25	-	pF
Output Capacitance ($V_{DS}=3.7\text{V}$, Level=30mVac@1MHz)	C_{oss}	-	1.8	-	pF
Input Capacitance ($V_{GS}=5\text{V}$, Level=30mVac@1MHz)	C_{iss}	-	8.0	-	pF

Typical Performances (In DuSemi Narrowband Test DEMO, 50 Ohm system)

Frequency=440MHz, $V_{DD}=3.7\text{Vdc}$, $I_{D(Q)}=90\text{mA}$, Pin=7dBm, $T_A=25^\circ\text{C}$

Output Power	P_{out}	-	151	-	mW
Power Gain	G_{PS}	-	15	-	dB
Drain Efficiency	η_D	-	50	-	%

Broad Band Evaluation Circuit (@VDD = 3.7V, f = 440 MHz)

Test Circuit Component Layout

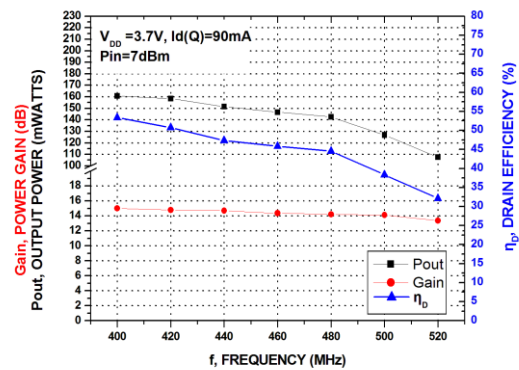
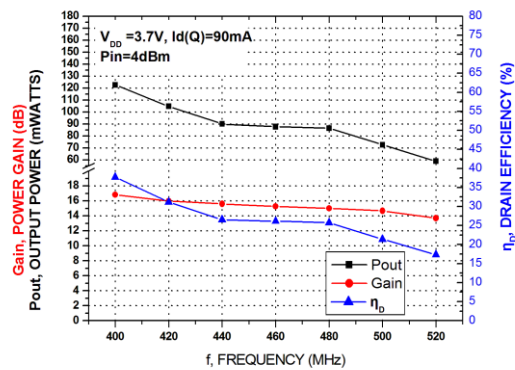
Table 5. Test Circuit Component Designations and Value

Part	Description	Part Number	Manufacturer
R3	470Ohm	—	—
R4	6.8KOhm	—	—
L1, L2	4.7nH	—	—
L3	8 Turns D: 0.5 mm, φ 2.4 mm Enamel Wire	—	—
C3,C15,	100pF Chip Capacitors	GQM21P5C1H101JB01	Murata
C4	18pF Chip Capacitors	GRM1885C1H201JA01	Murata
C12, C9	1000pF Chip Capacitors	GRM1885C1H102JA01	Murata
C10, C14,C7	10uF,25VChip Capacitors	—	—
C5	24pF Chip Capacitors	—	Murata
R1,R2,C1,C2,C8,C6	NC	—	—
U1	LM1117	—	—
PCB	FR-4 ,1.6mm, ε,4.5	—	—

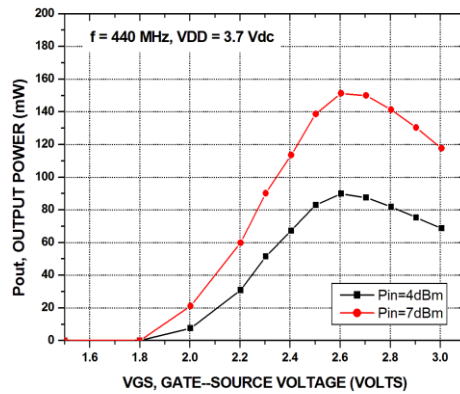
TYPICAL CHARACTERISTICS

1. Power Gain, Drain Efficiency and Output Power versus Frequency at a Constant Pin

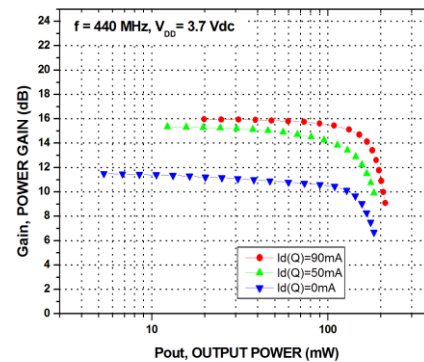
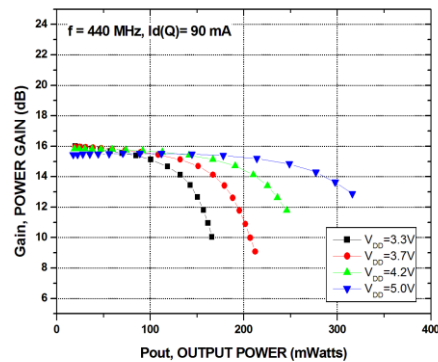
V_{DD}	$I_{D(Q)}$	Pin	Freq	Pout		Gain	η_D
[V]	[mA]	[dBm]	[MHz]	[dBm]	[mW]	[dB]	[%]
3.7	90	7	400	22.1	161	15.0	53.4
			440	21.8	151	14.7	47.4
			480	21.5	142	14.2	44.6
			520	20.3	107	13.4	32.1



2. Output Power versus Gate-Source Voltage @440MHz

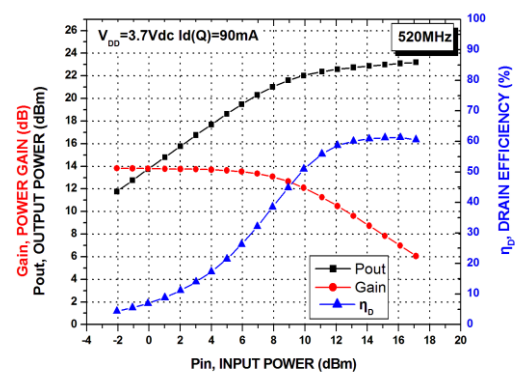
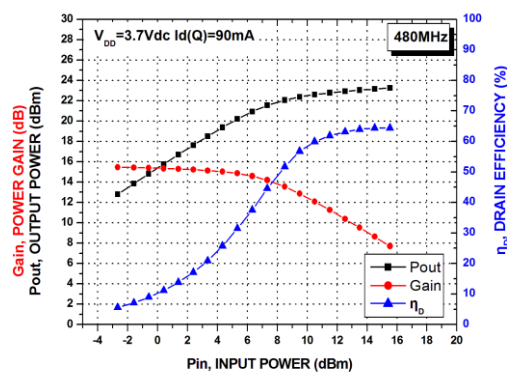
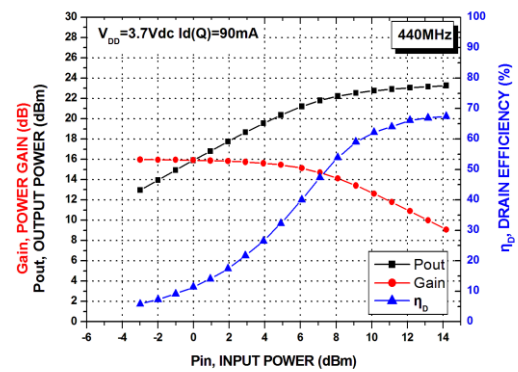
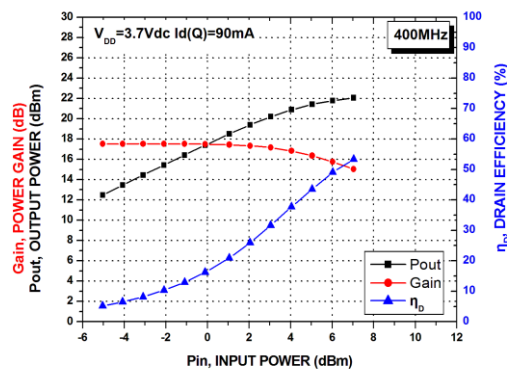


3. Power Gain versus Output Power@440MHz

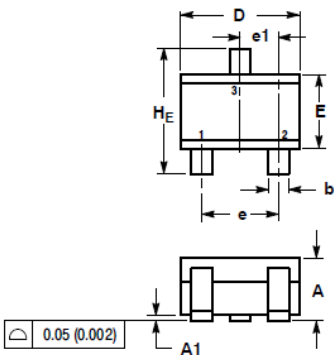


4. Power Gain, Drain Efficiency and Output Power versus Input Power

V_{DS}	$I_{D(Q)}$	Freq.	Gain	Pout		η_D
[V]	[mA]	[MHz]	[dB]	[dBm]	[mW]	[%]
3.7	90	400	17.5	22.0	160	53.4
		440	16.0	23.2	210	67.4
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PACKAGE

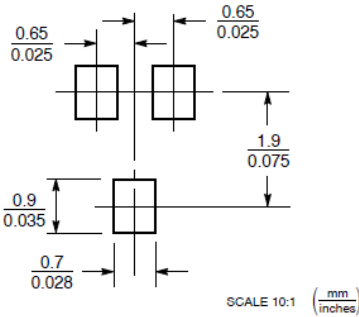


NOTES:

DIM	MILLIMETERS			INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.80	0.90	1.00	0.032	0.035	0.040
A1	0.00	0.05	0.10	0.000	0.002	0.004
A2	0.70 REF			0.028 REF		
b	0.30	0.35	0.40	0.012	0.014	0.016
c	0.10	0.18	0.25	0.004	0.007	0.010
D	1.80	2.10	2.20	0.071	0.083	0.087
E	1.15	1.24	1.35	0.045	0.049	0.053
e	1.20	1.30	1.40	0.047	0.051	0.055
e1	0.65 BSC			0.026 BSC		
L	0.20	0.38	0.58	0.008	0.015	0.022
H_E	2.00	2.10	2.40	0.079	0.083	0.095

STYLE 3:
PIN 1.gate
2.source
3.drain

SOLDERING FOOTPRINT*



REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
1	July 2018	Initial Release of Data Sheet